

4.7A, 30V, 0.031 Ohm, N-Channel, Logic Level UltraFET Power MOSFET



This N-Channel power MOSFET is manufactured using the innovative UltraFET process. This advanced process technology achieves the lowest possible on-resistance per silicon area, resulting in outstanding performance. This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, low-voltage bus switches, and power management in portable and battery-operated products.

Formerly developmental type TA76113.

Ordering Information

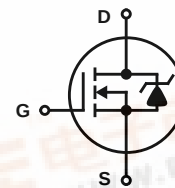
PART NUMBER	PACKAGE	BRAND
HUF76113T3ST	SOT-223	76113

NOTE: HUF76113T3ST is available only in tape and reel.

Features

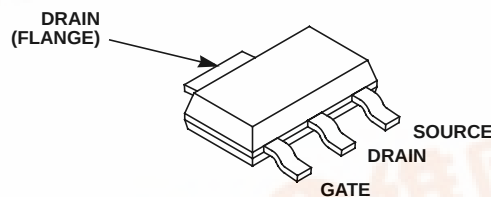
- Logic Level Gate Drive
- 4.7A, 30V
- Ultra Low On-Resistance, $r_{DS(ON)} = 0.031\Omega$
- Temperature Compensating PSPICE® Model
- Temperature Compensating SABER™ Model
- Thermal Impedance SPICE Model
- Thermal Impedance SABER Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Related Literature
 - TB334, "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging

SOT-223



HUF76113T3ST

Absolute Maximum Ratings $T_A = 25^{\circ}\text{C}$, Unless Otherwise Specified

	HUF76113T3ST	UNITS	
Drain to Source Voltage (Note 1)	V_{DSS}	30	V
Drain to Gate Voltage ($R_{GS} = 20\text{k}\Omega$) (Note 1)	V_{DGR}	30	V
Gate to Source Voltage	V_{GS}	± 16	V
Drain Current			
Continuous ($T_A = 25^{\circ}\text{C}$, $V_{GS} = 10\text{V}$) (Figure 2) (Note 2)	I_D	4.7	A
Continuous ($T_A = 100^{\circ}\text{C}$, $V_{GS} = 5\text{V}$) (Note 2)	I_D	2.7	A
Continuous ($T_A = 100^{\circ}\text{C}$, $V_{GS} = 4.5\text{V}$) (Note 2)	I_D	2.6	A
Pulsed Drain Current	I_{DM}	Figure 4	
Pulsed Avalanche Rating	E_{AS}	Figure 6	
Power Dissipation (Note 2)	P_D	1.1	W
Derate Above 25°C		0.0091	$\text{W}/^{\circ}\text{C}$
Operating and Storage Temperature	T_J, T_{STG}	-55 to 150	$^{\circ}\text{C}$
Maximum Temperature for Soldering			
Leads at 0.063in (1.6mm) from Case for 10s.	T_L	300	$^{\circ}\text{C}$
Package Body for 10s, See Techbrief 334	T_{pkg}	260	$^{\circ}\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}\text{C}$ to 150°C .

Electrical Specifications $T_A = 25^{\circ}\text{C}$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OFF STATE SPECIFICATIONS						
Drain to Source Breakdown Voltage	BV_{DSS}	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$ (Figure 12)	30	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA
		$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 150^{\circ}\text{C}$	-	-	250	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 16\text{V}$	-	-	± 100	nA
ON STATE SPECIFICATIONS						
Gate to Source Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$ (Figure 11)	1	-	3	V
Drain to Source On Resistance	$r_{DS(ON)}$	$I_D = 4.7\text{A}$, $V_{GS} = 10\text{V}$ (Figure 9, 10)	-	0.027	0.031	W
		$I_D = 2.7\text{A}$, $V_{GS} = 5\text{V}$ (Figure 9)	-	0.033	0.038	W
		$I_D = 2.6\text{A}$, $V_{GS} = 4.5\text{V}$ (Figure 9)	-	0.035	0.040	W
THERMAL SPECIFICATIONS						
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Pad Area = 0.173 in^2 (Note 2)	-	-	110	$^{\circ}\text{C}/\text{W}$
		Pad Area = 0.068 in^2 (See TB377)	-	-	133	$^{\circ}\text{C}/\text{W}$
		Pad Area = 0.026 in^2 (See TB377)	-	-	157	$^{\circ}\text{C}/\text{W}$
SWITCHING SPECIFICATIONS ($V_{GS} = 4.5\text{V}$)						
Turn-On Time	t_{ON}	$V_{DD} = 15\text{V}$, $I_D \cong 2.6\text{A}$, $R_L = 5.8\Omega$, $V_{GS} = 4.5\text{V}$, $R_{GS} = 18\Omega$ (Figure 15)	-	-	90	ns
Turn-On Delay Time	$t_{d(ON)}$		-	12	-	ns
Rise Time	t_r		-	46	-	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	31	-	ns
Fall Time	t_f		-	31	-	ns
Turn-Off Time	t_{OFF}		-	-	95	ns

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Electrical Specifications $T_A = 25^\circ\text{C}$, Unless Otherwise Specified

NOTES:

- Rated with $R_{\theta JA} = 110^\circ\text{C/W}$ measured using FR-4 board with 0.173 in^2 copper at 1000 seconds.

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V_{SD}	$I_{SD} = 4.7\text{A}$	-	-	1.25	V
		$I_{SD} = 2.7\text{A}$	-	-	1.00	V
Reverse Recovery Time	t_{rr}	$I_{SD} = 2.7\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	44	ns
Reverse Recovered Charge	Q_{RR}	$I_{SD} = 2.7\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	46	nC

Typical Performance Curves

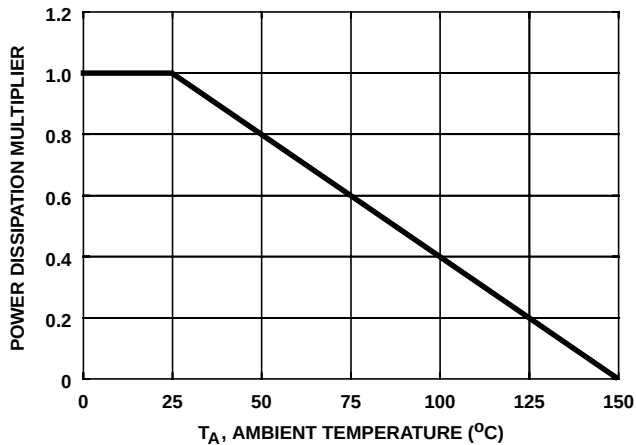


FIGURE 1. NORMALIZED POWER DISSIPATION vs AMBIENT TEMPERATURE

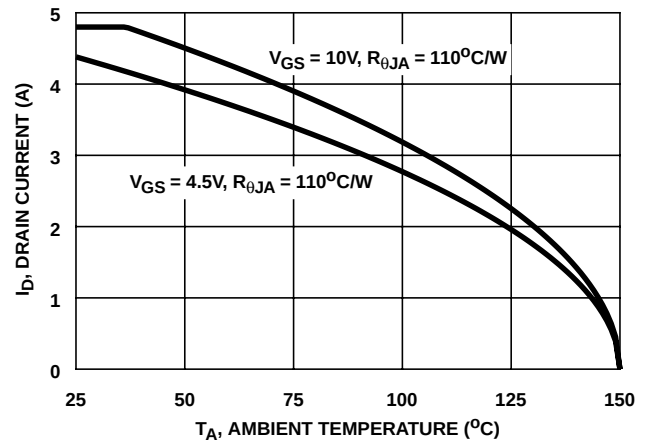


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs AMBIENT TEMPERATURE

Typical Performance Curves (Continued)

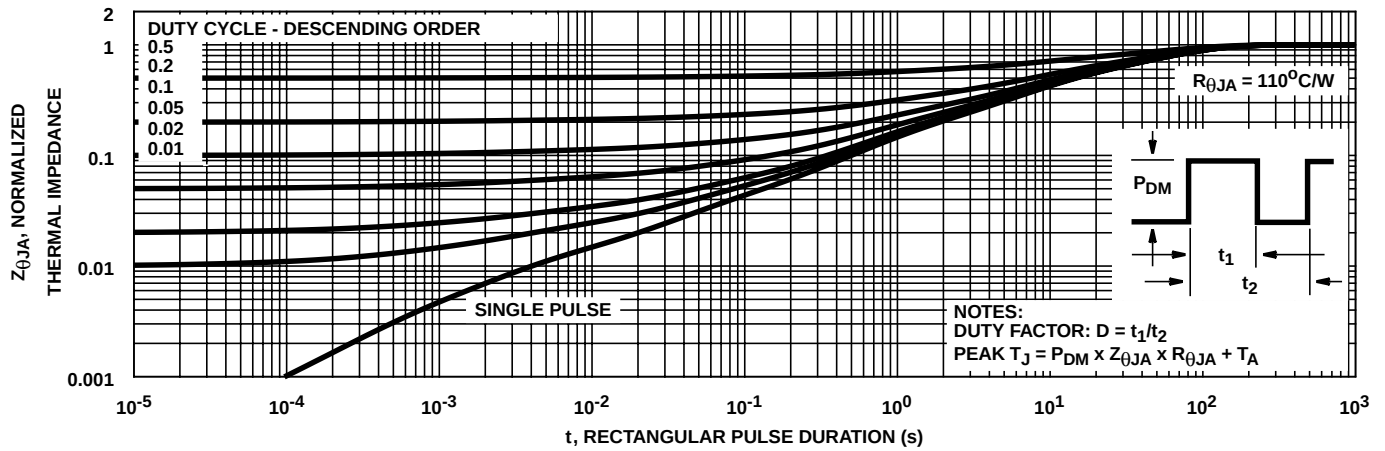


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

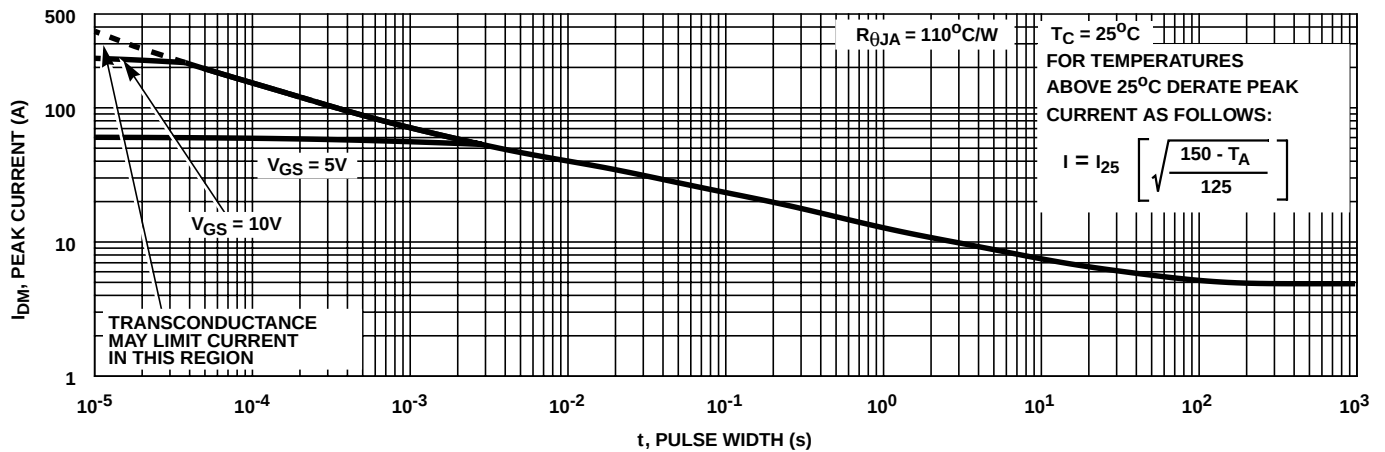


FIGURE 4. PEAK CURRENT CAPABILITY

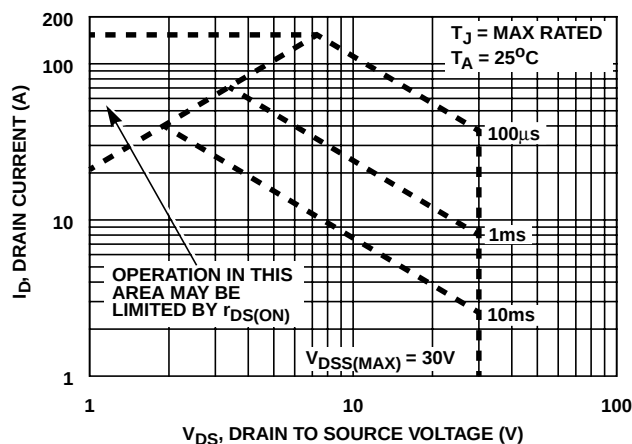
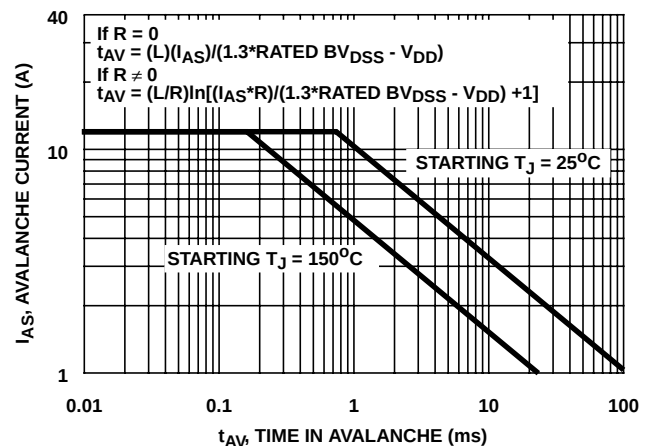


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Intersil Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

Typical Performance Curves (Continued)

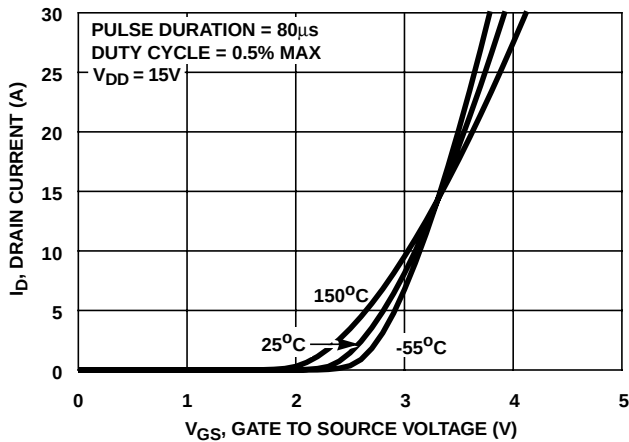


FIGURE 7. TRANSFER CHARACTERISTICS

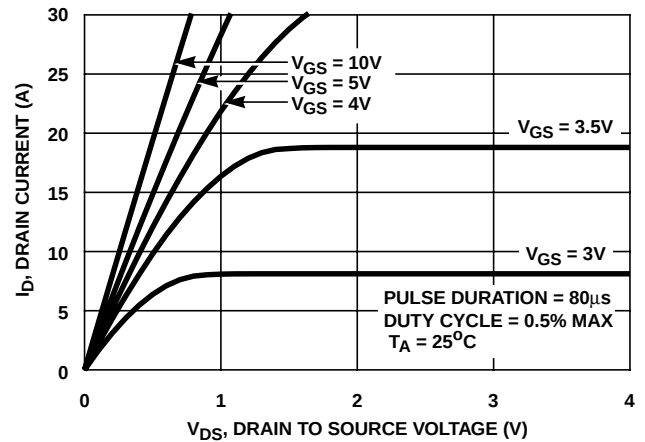


FIGURE 8. SATURATION CHARACTERISTICS

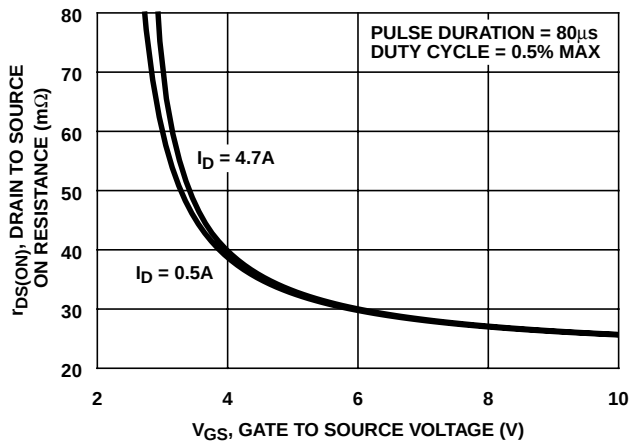


FIGURE 9. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

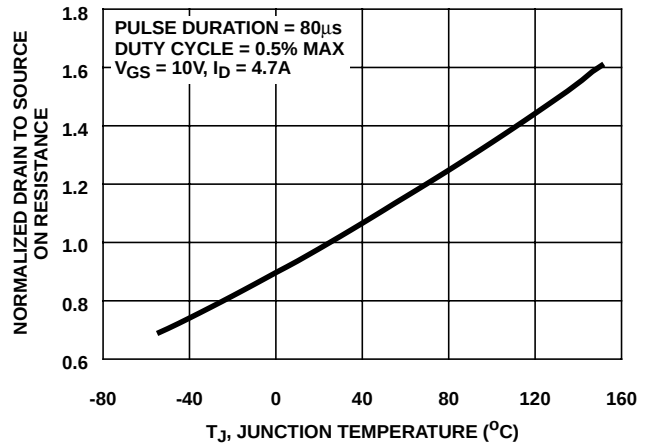


FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

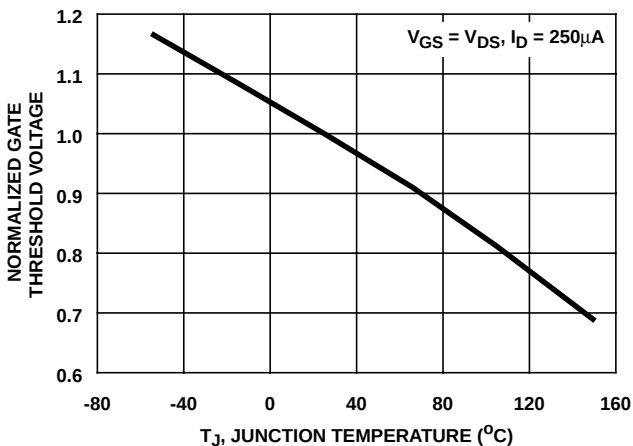


FIGURE 11. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

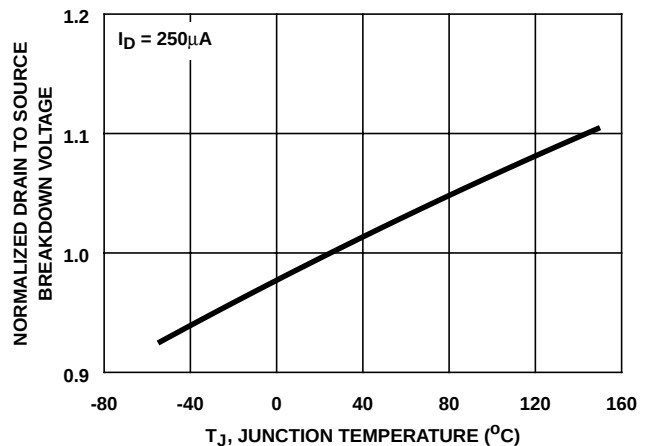


FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves (Continued)

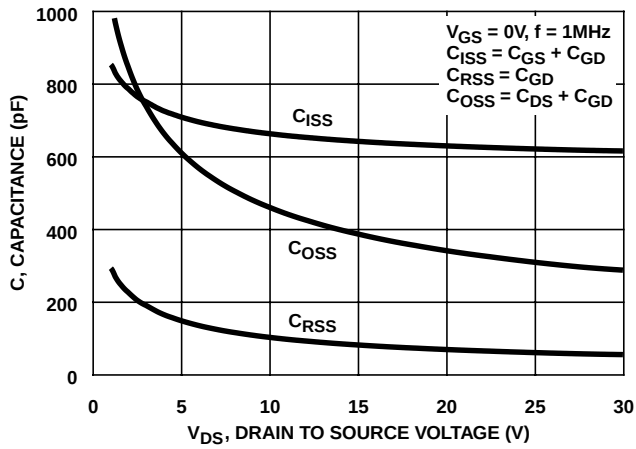
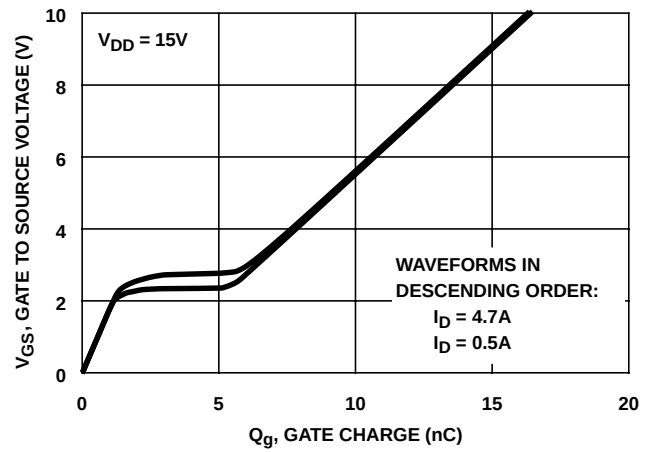


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Intersil Application Notes AN7254 and AN7260.

FIGURE 14. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

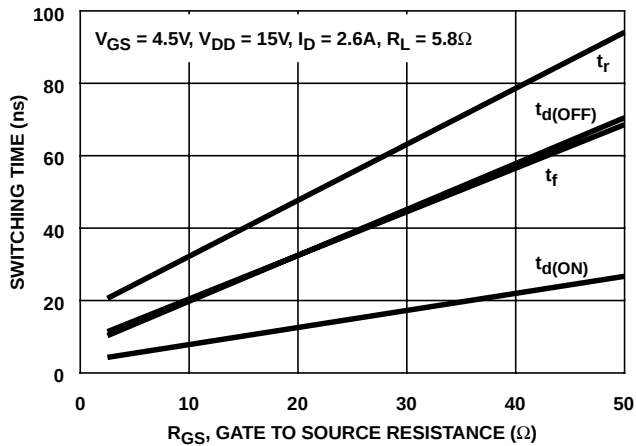


FIGURE 15. SWITCHING TIME vs GATE RESISTANCE

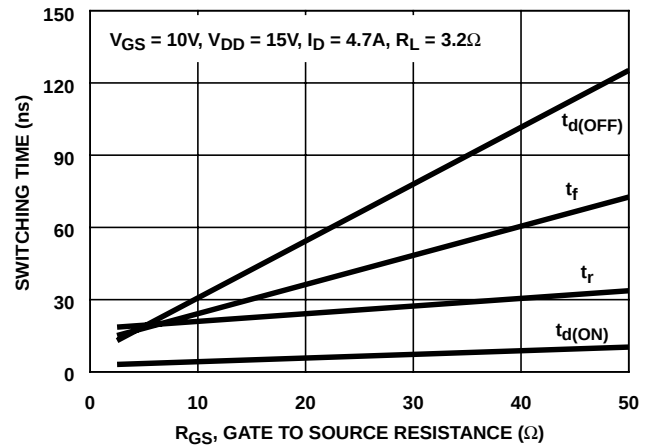


FIGURE 16. SWITCHING TIME vs GATE RESISTANCE

Test Circuits and Waveforms

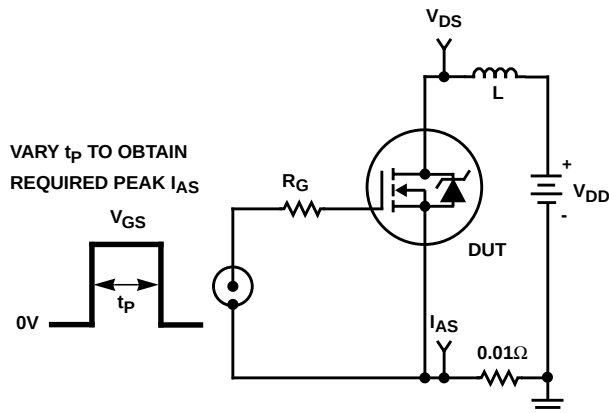


FIGURE 17. UNCLAMPED ENERGY TEST CIRCUIT

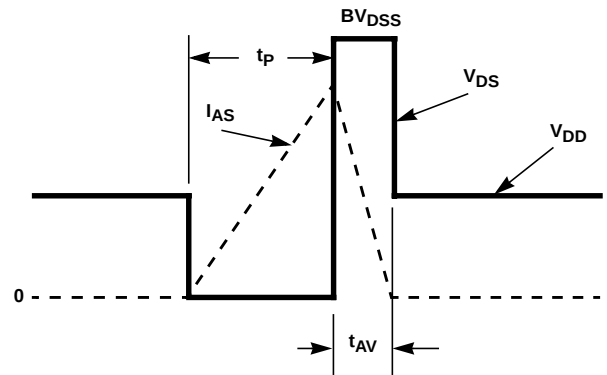


FIGURE 18. UNCLAMPED ENERGY WAVEFORMS

Test Circuits and Waveforms (Continued)

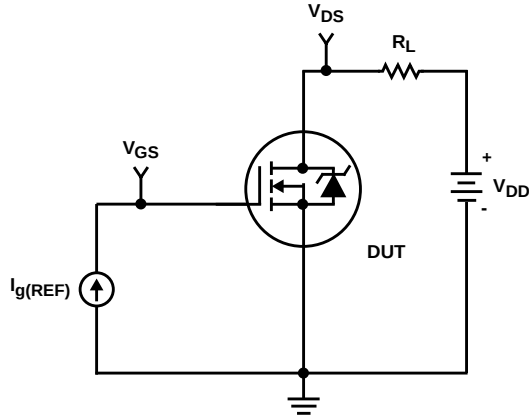


FIGURE 19. GATE CHARGE TEST CIRCUIT

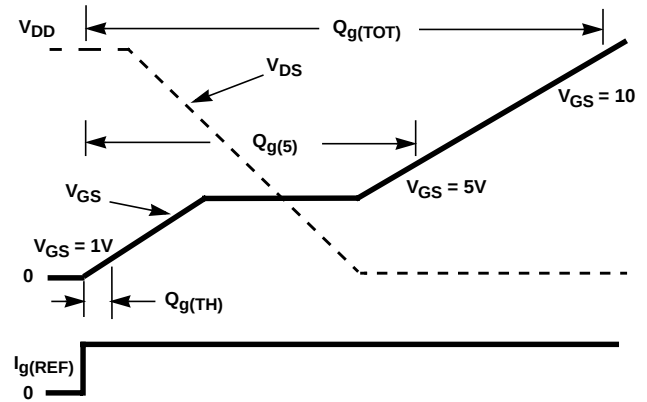


FIGURE 20. GATE CHARGE WAVEFORMS

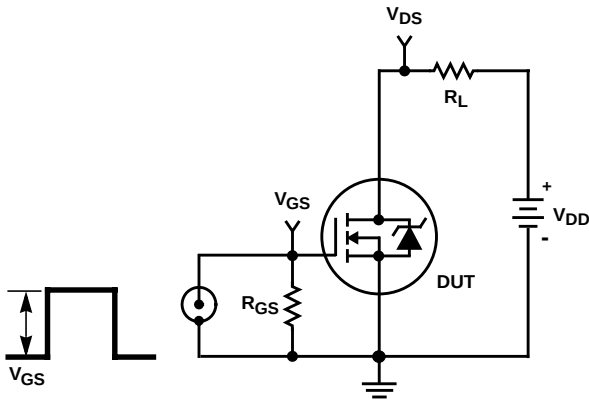


FIGURE 21. SWITCHING TIME TEST CIRCUIT

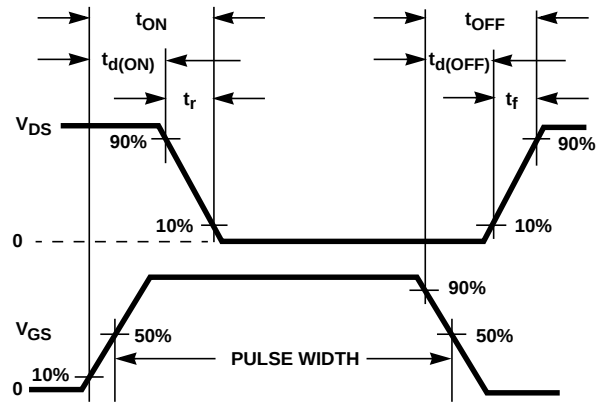


FIGURE 22. SWITCHING TIME WAVEFORM

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A ($^{\circ}\text{C}$), and thermal resistance $R_{\theta JA}$ ($^{\circ}\text{C}/\text{W}$) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{Z_{\theta JA}} \quad (\text{EQ. 1})$$

In using surface mount devices such as the SOT-223 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

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Intersil provides thermal information to assist the designer's preliminary application evaluation. Figure 23 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Intersil device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve. Displayed on the curve are $R_{\theta JA}$ values listed in the Electrical Specifications table. The points were chosen to depict the compromise between the copper board area, the thermal resistance and ultimately the power dissipation, P_{DM} . The smallest areas represent

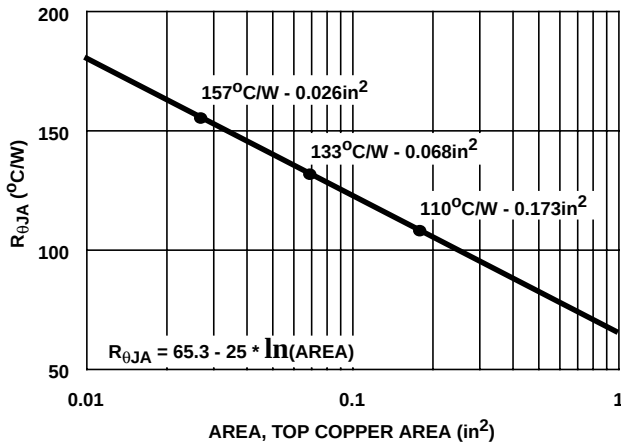


FIGURE 23. THERMAL RESISTANCE vs MOUNTING PAD AREA

the minimum bond pad area and the package outline area respectively as determined from the package diagram

Thermal resistances corresponding to other copper areas can be obtained from Figure 23 or by calculation using Equation 2. $R_{\theta JA}$ is defined as the natural log of the area times a coefficient added to a constant. The area, in square inches is the top copper area including the gate and source pads.

$$R_{\theta JA} = 65.3 - 25 \times \ln(\text{Area}) \quad (\text{EQ. 2})$$

The transient thermal impedance ($Z_{\theta JA}$) is also effected by varied top copper board area. Figure 24 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, C THERM1 through C THERM5 and R THERM1 through R THERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.

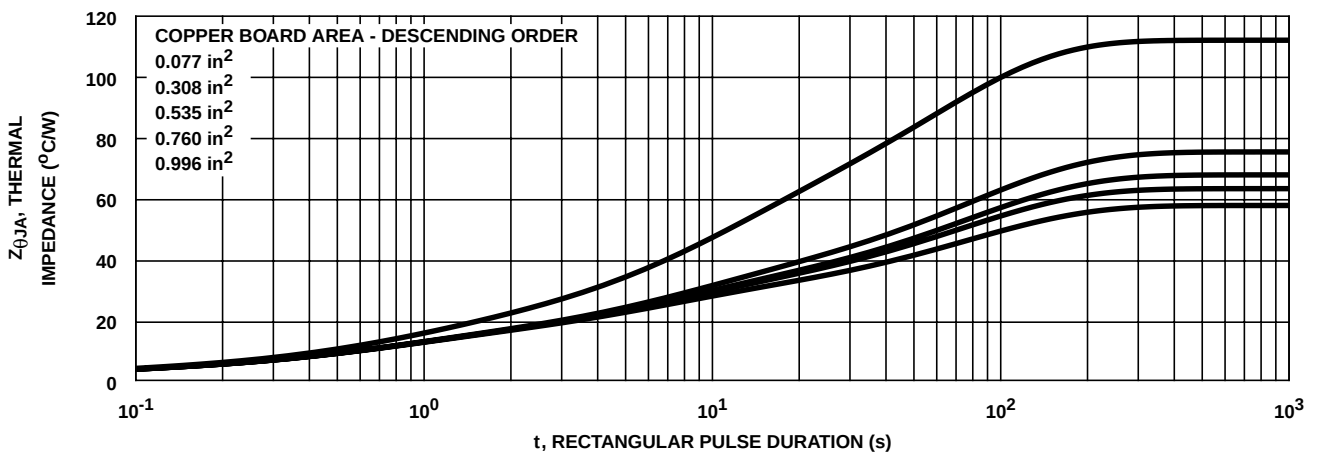


FIGURE 24. THERMAL IMPEDANCE vs MOUNTING PAD AREA

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SPICE Thermal Model

REV August 1998

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Copper Area = 0.077 in²

CTHERM1 th 8 1.9e-5

CTHERM2 8 7 9.5e-4

CTHERM3 7 6 1.9e-3

CTHERM4 6 5 3.5e-3

CTHERM5 5 4 2.0e-2

CTHERM6 4 3 6.5e-2

CTHERM7 3 2 2.4e-1

CTHERM8 2 tl 9.0e-1

RTHERM1 th 8 3.5e-3

RTHERM2 8 7 3.1e-2

RTHERM3 7 6 2.0e-1

RTHERM4 6 5 8.0e-1

RTHERM5 5 4 2.1

RTHERM6 4 3 11

RTHERM7 3 2 32

RTHERM8 2 tl 66

SABER Thermal Model

Copper Area = 0.077 in²

template thermal_model th tl

thermal_c th, tl

```
{
  ctherm.ctherm1 th 8 = 1.9e-5
  ctherm.ctherm2 8 7 = 9.5e-4
  ctherm.ctherm3 7 6 = 1.9e-3
  ctherm.ctherm4 6 5 = 3.5e-3
  ctherm.ctherm5 5 4 = 2.0e-2
  ctherm.ctherm6 4 3 = 6.5e-2
  ctherm.ctherm7 3 2 = 2.4e-1
  ctherm.ctherm8 2 tl = 9.0e-1
```

```
  rtherm.rtherm1 th 8 = 3.5e-3
  rtherm.rtherm2 8 7 = 3.1e-2
  rtherm.rtherm3 7 6 = 2.0e-1
  rtherm.rtherm4 6 5 = 8.0e-1
  rtherm.rtherm5 5 4 = 2.1
  rtherm.rtherm6 4 3 = 11
  rtherm.rtherm7 3 2 = 32
  rtherm.rtherm8 2 tl = 66
}
```

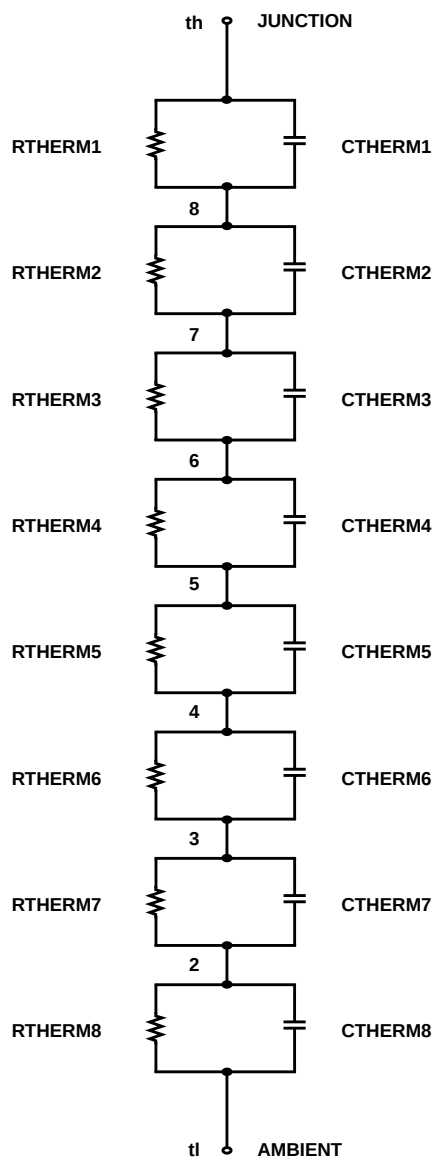


TABLE 1. THERMAL MODELS

COMPONENT	0.077 in ²	0.308 in ²	0.535 in ²	0.76 in ²	0.996 in ²
CTHERM6	6.5e-2	6.7e-2	6.7e-2	6.7e-2	6.7e-2
CTHERM7	2.4e-1	3.5e-1	3.5e-1	3.5e-1	3.5e-1
CTHERM8	9.0e-1	1.7	1.9	2	2.4
RTHERM6	11	9	9	9	9
RTHERM7	32	18	16	15.5	14.5
RTHERM8	66	45.5	40	36	31.5

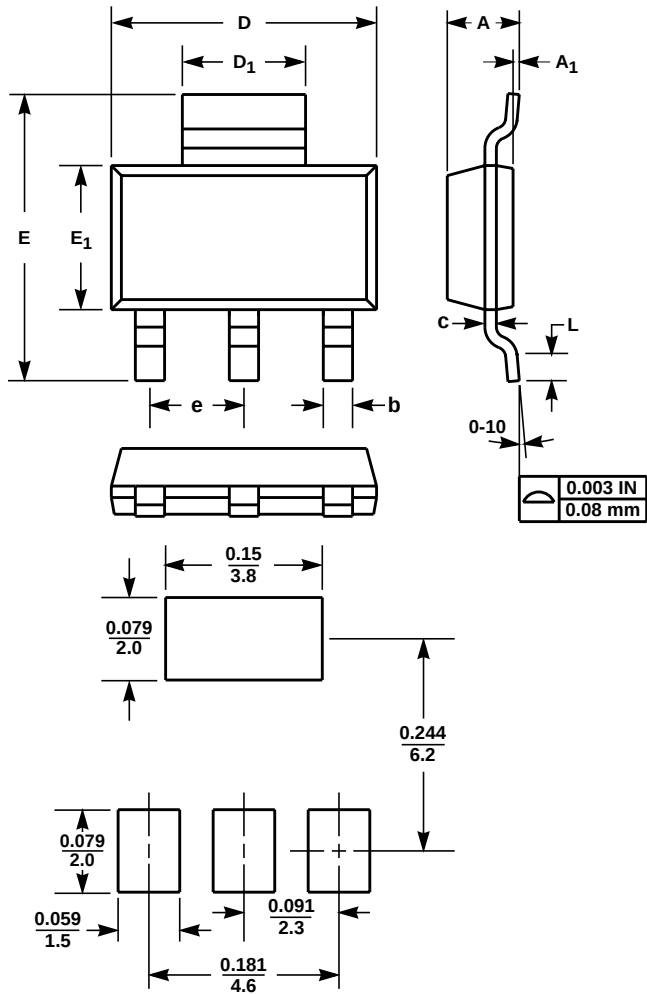
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HUF76113T3ST

SOT-223 (TO-261AA) SMALL OUTLINE TRANSISTOR



MINIMUM RECOMMENDED FOOTPRINT FOR
SURFACE MOUNTED APPLICATIONS

SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.063	0.070	1.60	1.78	-
A ₁	0.0008	0.004	0.02	0.10	-
b	0.026	0.033	0.65	0.85	-
c	0.010	0.014	0.25	0.35	-
D	0.248	0.264	6.30	6.70	-
D ₁	0.116	0.124	2.95	3.15	-
E	0.264	0.287	6.70	7.30	-
E ₁	0.130	0.146	3.30	3.70	2
e	0.0905 BSC		2.30 BSC		-
L	0.036	-	0.91	-	3

NOTES:

1. All dimensions are within the allowable dimensions of Rev. A of JEDEC TO-261 outline dated 1-90.
2. Dimension "E₁" does not include inter-lead flash or gate burr protrusions. Inter-lead flash and protrusions shall not exceed 0.010 inches (.25mm) per side.
3. "L" is the length of terminal for soldering.
4. Controlling dimension: Millimeter.
5. Revision 5 dated 5-99.

SOT-223 16mm TAPE AND REEL

